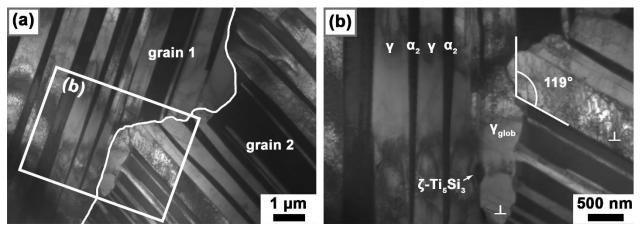
## In situ fracture observations of distinct interface types within a fully lamellar intermetallic TiAl alloy

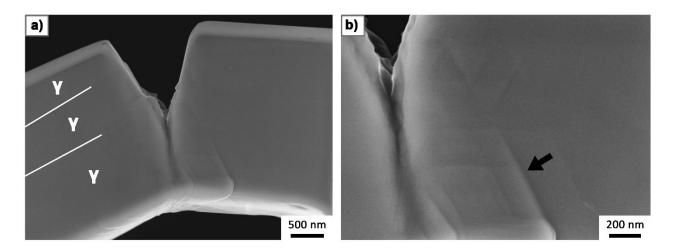
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**FIG. S1:** (a) TEM bright-field image of two  $\alpha_{2/\gamma}$ -colonies including a grain boundary. The insert constitutes a magnification of this grain boundary and is displayed in (b). Here a globular  $\gamma$  grain including a dislocation network together with an adjacent  $\zeta$ -Ti<sub>5</sub>Si<sub>3</sub> silicide is visible. The angle between the investigated grain boundaries was determined to be 119° and the presence of dislocation networks within  $\gamma$  lamellae was marked with the well-established symbols.



**FIG. S2**: (a) SEM SE image of (L)\_C2 cantilevers surface after the in-situ experiment and further bending to open the crack for SEM analysis. Therefore, the presence of band-like structures on the surface are more pronounced and they are better visible as in FIG. 2 (b). (b) displays a higher magnification of the present glide bands. With a black arrow, the same band was marked as in FIG. 2 (b).